

Search Notes

Application/Control No.

10/717,216

Examiner

Phi D. A

Applicant(s)/Patent under
Reexamination

IMAI, KATSUHIKO

Art Unit

3637

SEARCHED

Class	Subclass	Date	Examiner
52	167.1	6/11/2006	PA
	167.7		
	167.8		
	167.9		
	251		
	348		
	344		
	350		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR